Search Notes

Application/Control No.	Applicant(s)/Patent un Reexamination	nder
10/735,143	WASHIZAWA ET AL	
Examiner	Art Unit	
Thai Phan	2128	

SEARCHED					
Class	Subclass	Date	Examiner		
703	2	3/25/2007	T.P.		
703	6	3/25/2007	T.P.		
700	38	3/25/2007	T. P.		
700	47	3/25/2007	T.P.		
703	1	3/25/2007	T.P.		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO patent database	3/25/2007	îf.
NPL on_line search	3/25/2007	î. <i>[</i> ?
Inventorship search (bib. search)	3/25/2007	î- <i>[</i> ?